

<b>Notice of References Cited</b>	Application/Control No. 10/791,186	Applicant(s)/Patent Under Reexamination LEE ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0018348	01-2005	Lille et al.	360/128
*	B	US-2004/0240109	12-2004	Hamann et al.	360/126
*	C	US-2001/0013997	08-2001	Sasaki et al.	360/317
*	D	US-7,113,369	09-2006	Ota et al.	360/234.5
*	E	US-7,042,810	05-2006	Akiyama et al.	369/13.33
*	F	US-6,999,277	02-2006	Fontana et al.	360/126
*	G	US-6,831,802	12-2004	Gillis et al.	360/75
*	H	US-6,956,716	10-2005	Lille, Jeffrey S.	360/126
*	I	US-6,940,693	09-2005	Lille et al.	360/126
*	J	US-2004/0019638	01-2004	Makagon et al.	709/204
*	K	US-7,009,818	03-2006	Arnold et al.	360/320
*	L	US-7,035,047	04-2006	Hsiao et al.	360/126
*	M	US-6,909,674	06-2005	Ju et al.	369/13.17

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2005050511 A	02-2005	Japan	LILLE, JEFFREY S	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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